



## Product/Process Change Notice - PCN 19\_0048 Rev. -

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This notice is to inform you of a change that will be made to certain ADI products (see Appendix A) that you may have purchased in the last 2 years. **Any inquiries or requests with this PCN (additional data or samples) must be sent to ADI within 30 days of publication date.** ADI contact information is listed below.

**PCN Title:** ADP1055 Die and Data Sheet Revision

**Publication Date:** 21-Aug-2019

**Effectivity Date:** 23-Nov-2019 *(the earliest date that a customer could expect to receive changed material)*

### Revision Description:

Initial Release.

### Description Of Change:

Die Change:

1. Disable the Delayed Locked Loop's (DLLs) outputs to the pulse-width modulation (PWMs) on power-up, prior to download of EEPROM settings. Once EEPROM settings are downloaded, the DLLs' outputs are again enabled and function as normal.
2. Changed Die Revision ID register (0xAE - IC\_DEVICE\_REV) from default values of {0x01 0x11} to {0x01 0x12}.

Data Sheet Changes:

1. Change minimum on pulse of SYNC pin from 40ns to 160ns. (See page 8 on Data Sheet Revision B). Data Sheet change only – no silicon change.
2. Change data of Figure2 from {0xD3, 0x01, 0x00} to {0xD3, 0x00, 0x01}. (See figure on lower left column of page 55 on Data Sheet Revision B). Data Sheet change only - no silicon change.
3. Change Register IC\_DEVICE\_REV Description content from "0x01 0x11" to "0x01 0x12". (See Table 97 of page 81 on Data Sheet Revision B).

### Reason For Change:

Die changes:

1. To improve PWMs robustness during power-up due to fab process variations affecting Delayed Locked Loop's (DLL) performance on startup conditions.
2. Change revision ID to uniquely identify this silicon revision.

Data Sheet Changes:

1. Data Sheet errata change to correct minimum on pulse requirement of SYNC pin.
2. Data Sheet errata change to correct the order of the data bytes.
3. Change Register IC\_DEVICE\_REV default values to uniquely identify this silicon revision.

### Impact of the change (positive or negative) on fit, form, function & reliability:

No change to fit, form, function, or reliability.

### Summary of Supporting Information:

Qualification has been performed per Industry Standard Test Methods. See attached Qualification Results Summary. Data sheet changes will be reflected in Product Data Sheet Revision B.

### Supporting Documents

**Attachment 1: Type:** Qualification Results Summary

ADI\_PCN\_19\_0048\_Rev\_-\_Qualification Results Summary ADP1055.pdf

For questions on this PCN, please send an email to the regional contacts below or contact your local ADI sales representatives.

**Americas:**  
PCN\_Americas@analog.com

**Europe:**  
PCN\_Europe@analog.com

**Japan:**  
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**Rest of Asia:**  
PCN\_ROA@analog.com

**Appendix A - Affected ADI Models**

**Added Parts On This Revision - Product Family / Model Number (2)**

ADP1055 / ADP1055ACPZ-R7

ADP1055 / ADP1055ACPZ-RL

**Appendix B - Revision History**

<b>Rev</b>	<b>Publish Date</b>	<b>Effectivity Date</b>	<b>Rev Description</b>
Rev. -	21-Aug-2019	23-Nov-2019	Initial Release.

Analog Devices, Inc.

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